

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	09925397	CHANG ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Ehichioya, Fred I	2162

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
IEEE Xplore	12/16/07	FE
East (US-PGPub, USPat, EPO, JPO, Derwent).text search only	12/17/07	FE

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>